

Automated software-based in-field self-test program synthesis

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton International journal of microelectronics and computer science 2017 / p. 57-64 : ill

Automated software-based self-test generation for microprocessors

Jasnetski, Artjom; Ubar, Raimund-Johannes; Tšertov, Anton Proceedings of the 24st International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2017 : Bydgoszcz, Poland, June 19-21, 2014 2017 / p. 453-458 : ill
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New fault models and self-test generation for microprocessors using High-Level Decision Diagrams

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On automatic software-based self-test program generation based on high-Level decision diagrams

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Software-based self-test generation for microprocessors with high-level decision diagrams

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Using STLs for effective in-field test of GPUs

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